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As a consequence, there is a difference in amplifier gain  $(K_v = R_{feedback} / R_{input})$  control. In the Applicants' circuit,  $K_v = R_{DS} / R_i = (1/R_i) R_{DS}$ , where  $R_{DS}$  is a function of  $V_{GS}$ , so that there is a linear dependence between  $K_v$  and  $R_{DS}$ . Pechstein, in contrast, discloses that  $K_v = R_f / R_{DS}$ , which is a *non*linear dependence between  $K_v$  and  $R_{DS}$ .

(2)  $V_{GS}$  is analogous to the Applicants' output signal  $V_{out}$  (Fig. 3) which is measured at the output of the amplifier. In Pechstein,  $V_{GS}$  is the drain potential.

The consequence of this difference is in the circuit loading during measurement. In the Applicants' case, the circuit (the operating point for the ISFET) is not loaded during measurements. In the case of Pechstein, to keep inaccuracy levels at  $\pm$  0.1  $\mu$ A, the input resistance of the voltmeter, used for measurements, must be greater than 10 megohms.

(3) Finally, the Applicants have replaced a "floating" Zener diode by a <u>summing</u> amplifier, while Pechstein still uses a Zener diode for the reference voltage.

Respectfully submitted.

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Nick Bromer (Reg. No. 33,478)

RABIN & BERDO, P.C. CUSTOMER NO. 23995

Telephone: (202) 371-8976 Telefax: (202) 408-0924

I certify that this correspondence is being facsimile transmitted to the U.S. Patent and Trademark Office (Fax No. 703-872-9306) on January 28, 2005.

Nick Bromer [Reg. No. 33,478]

**AMENDMENT** 

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